

Scenario-based Mixed Signal Layout Generator using Generation APIs for Memory

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Motivation

- **Needs for Scenario-based Mixed Signal Layout Generator for Memory Analog IP**

- The turn-around-time (TAT) for analog IP layout design significantly exceeds that for digital, despite their low quantity (Fig. 1 (a), (b)).
- Although automated migration and generation solutions for analog IP have been proposed recently, their practical implementation remains challenging.
 - Parts of the schematic may be modified, or a new schematic can be added, which leads to the previous layout information no longer being applicable.
 - Even when the schematic is reused, layout reusability is often hindered by changes in design rule (DR), boundary condition, etc. (Fig. 2).
 - In the case of layout generation solutions, there is an issue of unpredictability regarding how much time it will take to update the layout based on the changes.
- Transitioning to a new process requires layout exploration to select the optimal layout based on area and characteristics, but drawing multiple layouts manually takes excessively long.

→ **A solution is needed to quickly generate new layout in response to changes.**

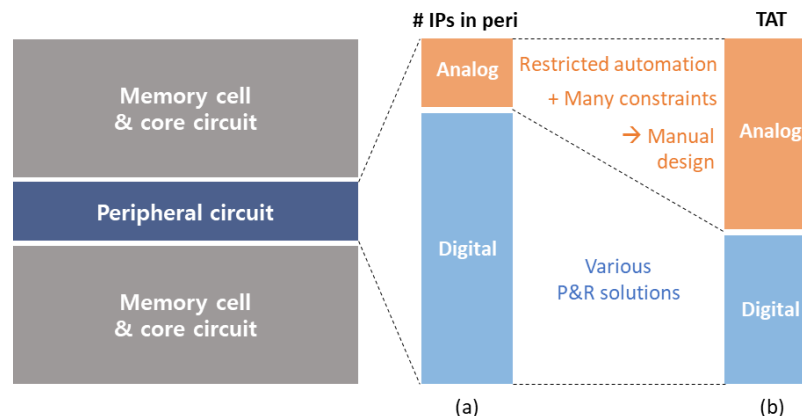


Fig. 1. Composition in peripheral circuit for memory.



Fig. 2. Layout changes in a IP with the same schematic.
Different color represents the floorplan area for different type of components*.

Motivation (cont.)

- **Advantages of Proposed Methods**

- Layouts migrated from the previous one can be generated in real time.
- When changes to the layout pattern are required, new layouts can be generated with simple modifications through the UI without the need to directly modify the generation code.
- Rapid layout modifications enable layout exploration, allowing engineers to compare areas, characteristics, and other factors to make better decisions (Fig. 3).

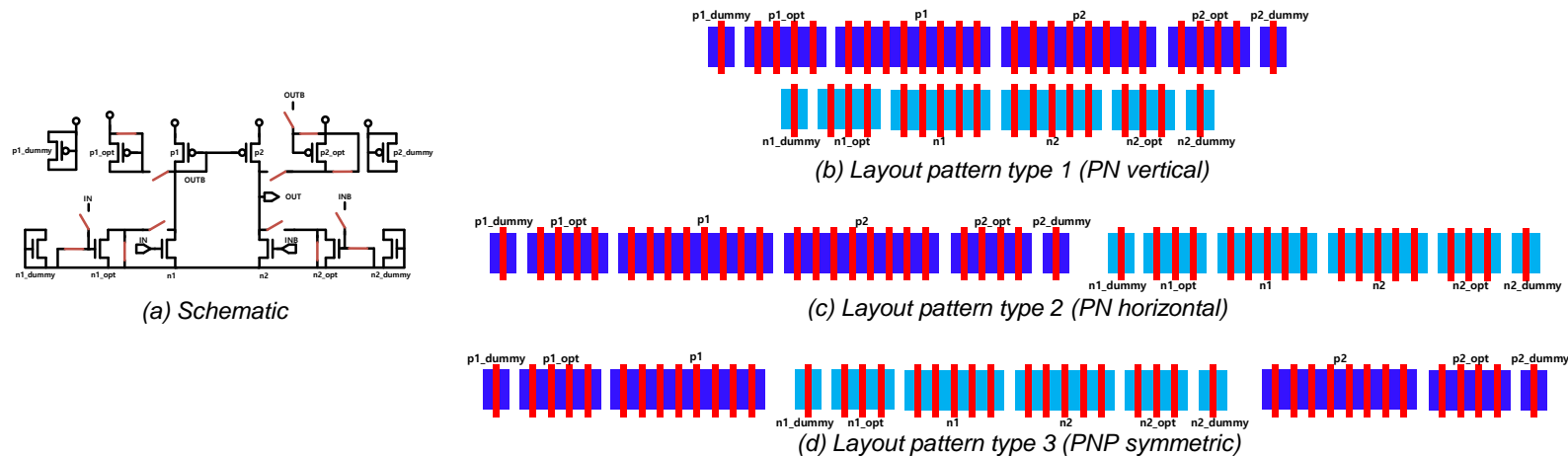
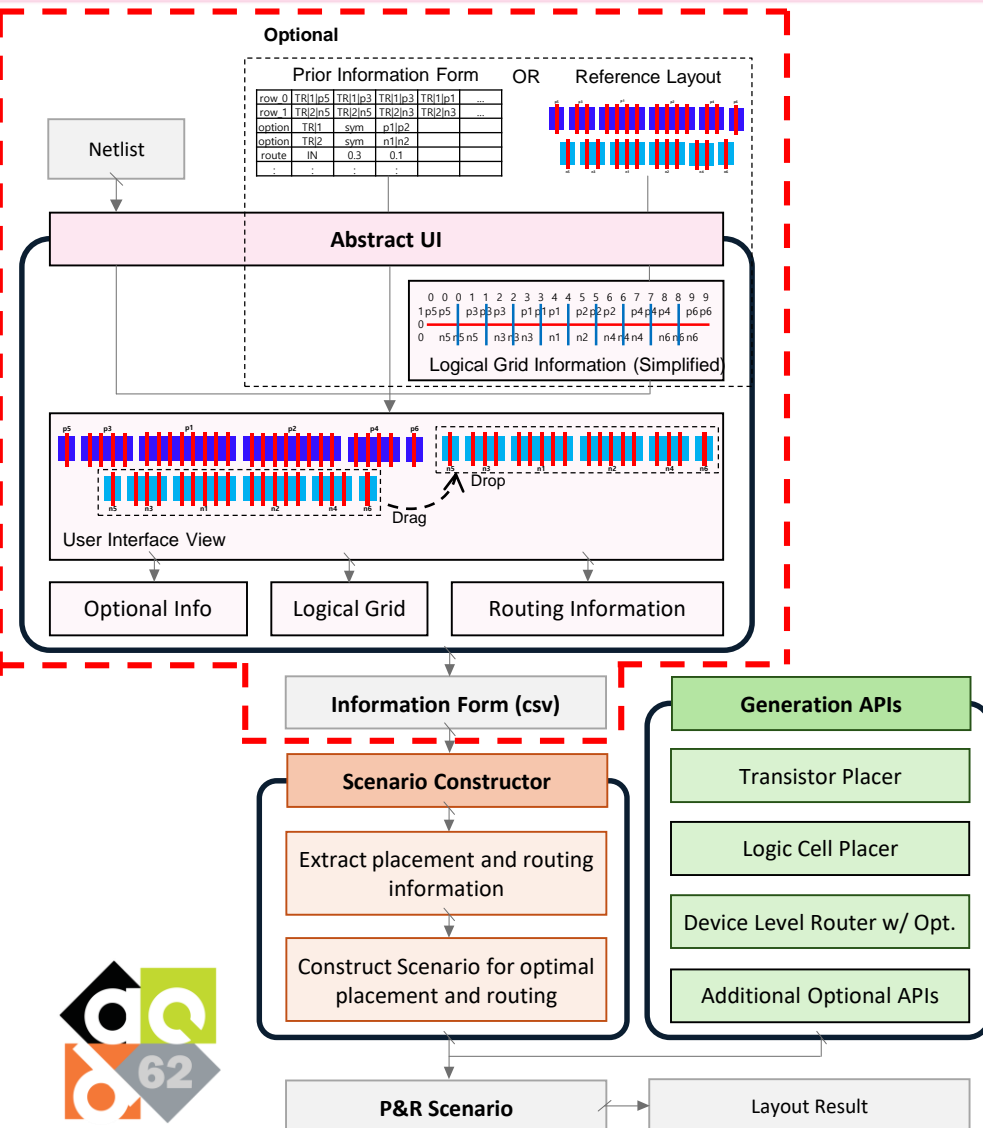


Fig. 3. Layout changes in a IP with the same Differential Amplifier schematic with option.

Proposed Flow



- **Abstract UI (User Interface)**

- It receives a netlist and displays initial placement results, considering routing, in a layout similar to the actual one.
- When a reference layout or prior information form is provided, it extracts logical grid and adjusts it to match the netlist for display.
- Engineers can easily modify the placement or routing to match their desired layout.
- Information Form is generated from the abstract layout in UI, which contains the placement logical grid, routing information, and additional optional information(e.g. symmetry, alignment, etc.).

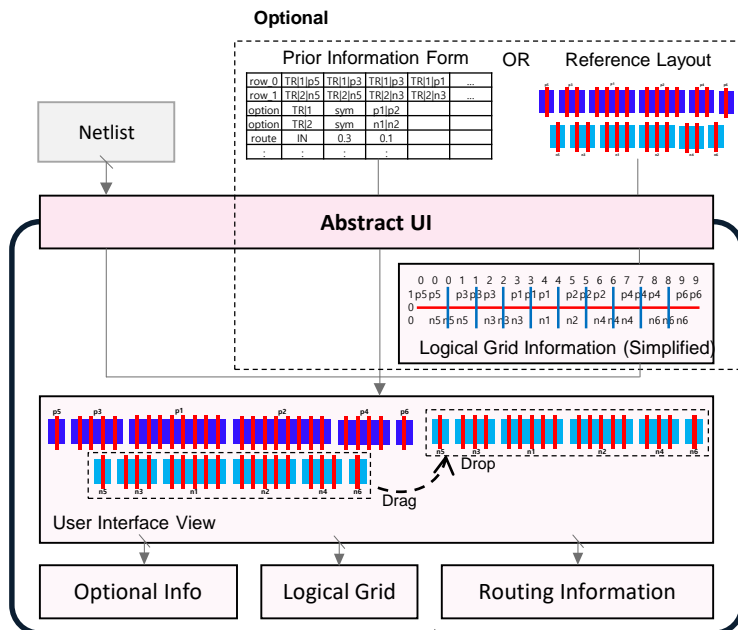
- **Information Form (csv)**

- The information of each devices is stored with distinctions based on category*, index**, and instance name.
- The routing information from the UI is converted into a width that reflects the position and non-default routing (NDR), then applied.



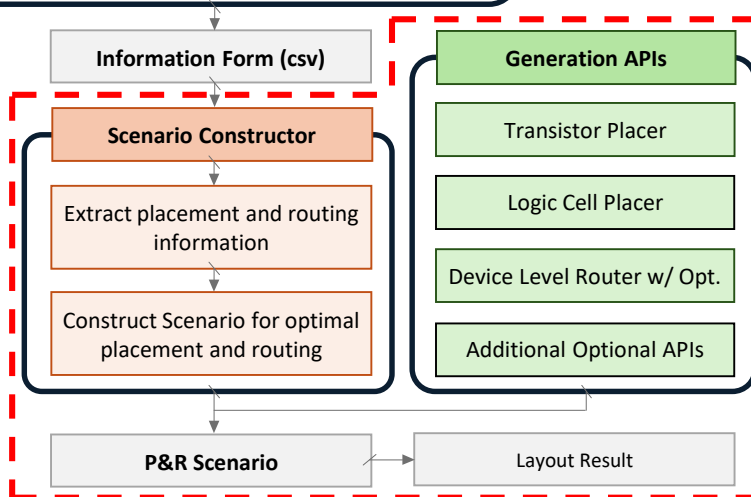
Fig. 4. Overall flow of Scenario-based Layout Generator

Proposed Flow (cont.)



Scenario Constructor

- The placement and routing information of devices are extracted from the Information Form.
- A Scenario is constructed, which means organizing the sequence of placement and routing (P&R) while considering the dependencies between individual elements (devices to be placed or nets to be routed), to achieve the desired layout.



P&R Scenario

- Placement and routing are performed according to the given scenario sequence, utilizing APIs such as the Transistor Placer, Logic Cell*** Placer, Device-Level Router with Option Layer, and Additional Optional APIs.
- This process enables the creation of new layouts without modifying the actual code.
- Each API within the Generation APIs independently and fully performs its designated tasks.



Fig. 4. Overall flow of Scenario-based Layout Generator

Detailed Information of Generation APIs

- **Generation APIs**

- **The Transistor Placer** receives logical grid information which contains the relative relationship of the transistors and converts it into physical placement.
 - It minimizes the area by 1) finding optimal spacing between transistors, maintaining relative position and considering DRs, and 2) sharing the diffusion with the same net.
 - It allows for various output to be generated for the same transistor, depending on the options provided.
 - e.g. diffusion sharing, using antenna, symmetric constraints and etc.
- **The Logic Cell Placer** arranges logic cells with the same index within the same row
 - Avoid blocked ports and minimize the use of routing resources.
- **The Device-Level Router** performs routing to the desired tracks, including NDR, shielding, and **optional routing**, ensuring the shortest possible path.
 - It is designed to prioritize the use of specified tracks.
 - Routing tracks need to be specified for effective connections with the upper hierarchy or neighboring layouts, as well as for characteristic-specific requirements.
 - It is also designed to support various optional routing tasks for ECO purposes.
- **The Additional Optional APIs** include handling other categories such as guarding and another layout structures, as well as post-processes for tasks like Design Rule Check.

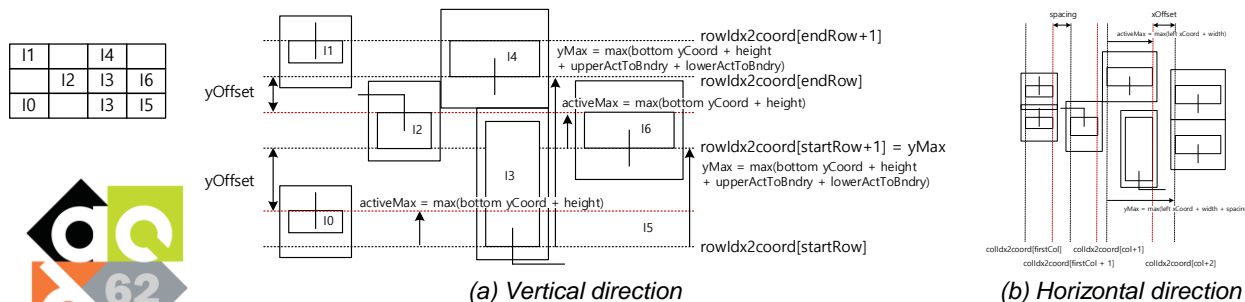


Fig. 5. Conversion logic of grid for each direction in transistor placement

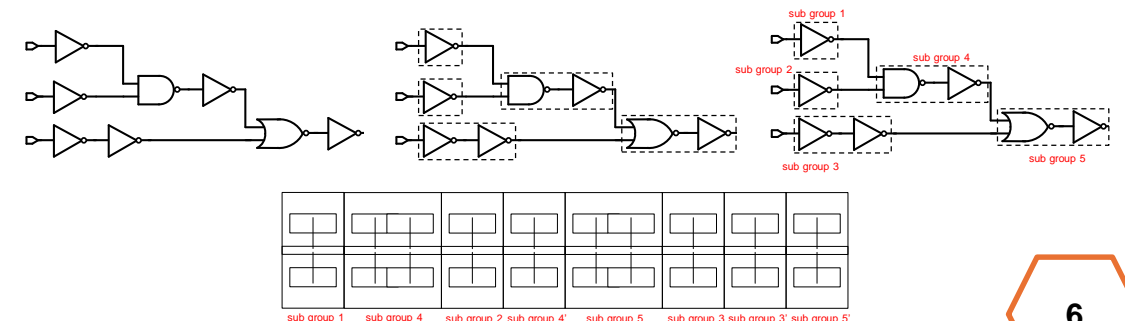


Fig. 6. Logic Cell placement

Environment & TAT Comparison

- Run on Linux machine with Intel Xeon® Gold 6334 CPU
- Implemented with Python and Skill Language
- Use two IPs for the experiment (Table 1)
- The Information Form used for measuring the runtime of the P&R Scenario was extracted from the reference layout.
- It has been observed that the TAT for manual layout processes can be reduced by approximately 99.65% for Latch-up Prevention Circuit and 99.88% for Differential Amplifier.

IP	TAT				
	Manual Drawing	Manual Drawing + Generation APIs Only			Runtime of P&R Scenario
Latch-up Prevention Circuit	2h	1h	-50%	25s	-99.65%
Differential Amplifier	8h	1h	-87.5%	34s	-99.88%

Table 1. TAT comparison



Experimental Results

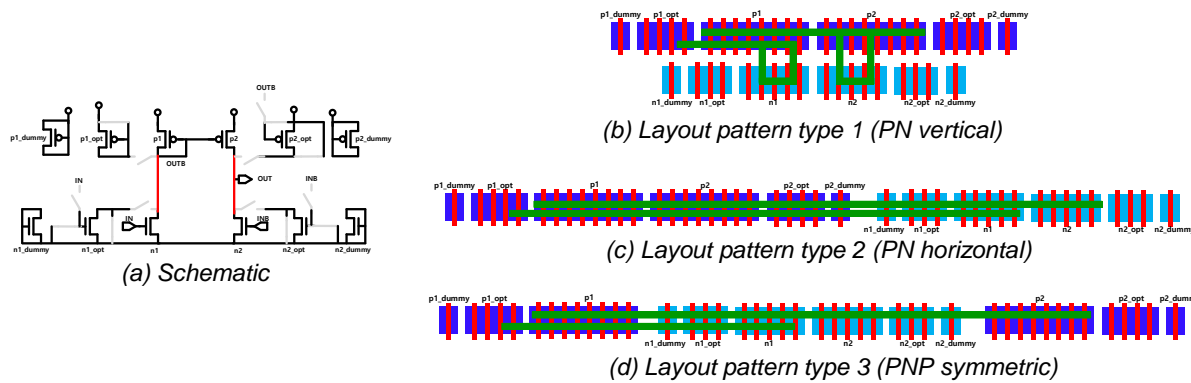


Fig. 6. Layout exploration results of Differential Amplifier

Differential Amplifier	Area(μm^2)	Symmetry	Critical Net WL (μm)	Total WL (μm)	Modifying Time
Type 1 (PN Vertical)	100.869	O	37.3787	90.9811	Ref.
Type 2 (PN Horizontal)	89.1822	X	80.8479	156.5476	< 10 min.
Type 3 (PNP Symmetric)	92.4111	O	66.5035	141.9633	< 10 min.

Table 2. Comparison between layout pattern types

- Red lines in Fig. 6. (a) and green lines in (b) ~ (d) represent critical nets in Differential Amplifier.
- Using the same schematic, three types of layouts (Fig. 6. (b) ~ (d)) were generated by making simple modifications to the transistor placement through the UI.
- Modifying Abstract UI for the placement and routing takes less than 10 minutes.
- From an area perspective, Type 2 is optimal; however, when considering symmetry along with a combination of area and net wire length, Type 1 or Type 3 can be selectively the optimal solution depending on specific cases (Table 2).

Summary

- A **Scenario-Based Mixed Signal Layout Generator** was developed to significantly reduce layout TAT and enable efficient pattern exploration.
- The approach supports rapid pattern adjustments, allowing engineers to interact with the tool and generate layouts in their desired patterns.
- It is capable of handling complex patterns, including those utilizing optional routing and advanced layout configurations.
- By simply inputting a netlist, the tool analyzes the schematic to generate new layout patterns while ensuring compliance with analog layout constraints.
- This automation reduces manual effort for engineers, allowing them to focus on high-level design optimizations.
- **Contribution**
 - **Enhanced productivity:** Demonstrated substantial reductions in layout TAT.
 - **Reduced complexity:** Simplified adjustments for new design constraints or circuit modifications.
 - **Improved quality:** Facilitated exploration of multiple patterns, ensuring better silicon performance.
- **Future Work**
 - While the proposed work assists engineers in generating desired patterns and supports exploration, future developments aim to automate the exploration process entirely, including characteristic comparisons(e.g. post-layout simulation), to further enhance efficiency and accuracy.

